

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0142333	07-2003	Nguyen et al.	358/1.11
*	B	US-2001/0043214	11-2001	NAKATSUJI et al.	345/471
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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